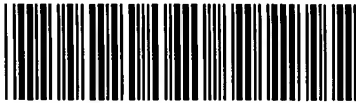


Search Notes



Application/Control No.

10/523,778

Examiner

Tran N. Nguyen

Applicant(s)/Patent under Reexamination

TANIGUCHI ET AL.

Art Unit

2834

SEARCHED

Class	Subclass	Date	Examiner
310	156.08	11/	JNP
	156.36	127/	
	156.39	107	
	156.53		
	156.56		
	156.57		
	156.75		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
(H02K001/22-27)	11/	JNP
and. (magnet same (degree angle))	127/	
	107	